

Atomic Spectroscopy Virtual Symposium

Mark your calendar

Date: 3-4 March, 2021

Doors open at: 07:45 GMT |
08:45 CET | 02:45 EST | 15:45 SGT

Welcome to the Atomic Spectroscopy Virtual Symposium

An event brought to you by Agilent and Wiley bringing together the Atomic Spectroscopy community together in a virtual format. Spanning across the Atomic Spectroscopy portfolio of products, we aim to provide a varied agenda to tempt Atomic Spectroscopists from across the globe.

Live Sessions:

08:00 GMT 09:00 CET 03:00 EST 16:00 SGT	Agilent's Innovations Hour - Spectroscopy Supplies <i>Speaker: Eric Vanclay, Agilent, Australia</i>
09:00 GMT 10:00 CET 04:00 EST 17:00 SGT	Determination of organic and inorganic forms of As, Se and Sb in foods using ICP-MS and their applications <i>Speaker: D.ssa Maria Chiara Fontanella from Università Cattolica Sacro Cuore of Piacenza, Italy</i>
09:00 GMT 10:00 CET 04:00 EST 17:00 SGT	Using the ICP-MS/MS technology in the field of nuclear safety and radiological protection <i>Speaker: Alkis Gourgiotis, IRSN Fontenay-aux-Roses, France</i>
10:00 GMT 11:00 CET 05:00 EST 18:00 SGT	Detection of trace elements and heavy metals in food and from food contact materials using Agilent's Triple-quad ICP-MS 8800 <i>Speaker: Dr. Karlien Cheyns, Belgian Health Institute Sciensano, Belgium</i>
10.30 GMT 11:30 GMT 05:30 EST 18.30 SGT	Radionuclides for decommissioning (Tc-99, Mo-93, Ca-41) and nuclear medicine <i>Speaker: Ben Russell, NPL, UK</i>
11:00 GMT 12:00 CET 06:00 EST 19:00 SGT	ICP-MS, food and the big 4 <i>Speaker: Barbro Kollander, Swedish Food Agency, Sweden</i>
12:00 GMT 13:00 CET 07:00 EST 20:00 SGT	Absolute quantification of biomolecules by ICP-MS/MS <i>Speaker: Prof. Jorge Ruiz Encinar, University of Oviedo, Spain</i>
13:00 GMT 14:00 CET 08:00 EST 21:00 SGT	Single-event ICP-MS for single-entity analysis <i>Speaker: Eduardo Bolea Fernandez, University of Ghent, Belgium</i>
14:00 GMT 15:00 CET 09:00 EST 22:00 SGT	Pharma quality control – Elemental impurities in drug products following ICH Q3D /USP 232 guidelines <i>Speaker: Andrew Brotherhood, Agilent, UK</i>
15.30 GMT 16:30 CET 10:30 EST 23:30 SGT	ICP-MS for ultra-trace determination of ²³⁸ U and ²³² Th for dark matter detectors <i>Speaker: Jim Dobson, University College London, UK</i>
21:00 GMT 22:00 CET 16:00 EST 05:00 SGT	Agilent's Innovations Hour - Spectroscopy Supplies <i>Speaker: Eric Vanclay, Agilent, Australia</i>

Panel Discussion:

15:00 GMT | 16:00 CET
10:00 EST | 23:00 SGT

Part I: How to successfully write a research article &
Part II: Maximize the impact of your published research
Speakers: Paul Trevorrow, Executive Journals Editor, Wiley & Dr. Christina Poggel, Editor-in-Chief,

18:00 GMT | 19:00 CET
13:00 EST | 05:00 SGT

Back to Basics: An overview of Agilent ICP-MS and ICP-MS/MS in the Semiconductor Industry
Speakers: Yan Cheung, Abe Gutierrez, Emmett Soffey & Bert Woods, Agilent, USA

ICP-QQQ:

- LA- ICP-MS/MS for geological applications: from volcanic halogens to Mars2020
Speaker: Benoit Caron, Sorbonne Universit e, France
- Essential hardware features of an ICP-MS/MS - how Agilent reimagined ICP-MS - Part 1
Speaker: Jenny Nelson, Agilent, USA
- What advantages does ICP-MS/MS offer your lab? Current and future applications of ICP-MS/MS - Part 2
Speaker: Jenny Nelson, Agilent, USA
- Analysis of nanoparticles in food by single particle ICP-MS
Speaker: Kathrin Loshner, National Food Research Centre, Denmark

General Atomic Section:

- Speciation made simple with Agilent ICP-MS
Speaker: Jonathon Talbott, Agilent, USA
- Analytical Plasma Fundamentals and the impact on your results
Speaker: Yan Cheung, Agilent, USA
- Are ICP-OES interferences giving you concern? Learn how to remove spectral interferences and improve accuracy on ICP-OES
Speaker: Sima Singha, Agilent, USA
- Are your ICP-OES results optimized? Discover how to simplify method development and data analysis on ICP-OES
Speaker: Sima Singha, Agilent, USA
- Avoid common time traps in ICP-MS analysis – a virtual workshop!
Speaker: Bert Woods, Agilent, USA
- Discover an automated sample screening that intelligently develops ICP-OES methods
Speaker: Greg Gilleland, Agilent, USA
- Effortless trace elemental analysis, avoid time traps with smart ICP-MS
Speaker: Craig Jones, Agilent, USA
- Geochemical analysis at the speed of light with ICP-OES
Speaker: Ana Garcia-Gonzalez, Agilent, USA
- Learn how to confirm your data on ICP-OES. Are you getting the right result? Are you sure?
Speaker: Paul Krampitz, Agilent, USA
- Measuring nanoparticles in the environment with your ICP-MS
Speaker: Jonathon Talbott, Agilent, USA
- Rapid multielement nanoparticle analysis with sNP-ICP-MS
Speaker: Craig Jones, Agilent, USA

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- The mining lifecycle and elemental analysis workshop (Part 1 - 3)
Speaker: Paul Krampitz, Agilent, USA
- The new Agilent ICP-OES give us 17 seconds and we'll save you days of method development time, and double your productivity
Speaker: Paul Krampitz, Agilent, USA
- An overview of the Atomic Spectroscopy Portfolio
Speaker: Nikolay Kovachev, Agilent, Spain
- Accurate elemental analysis in petrochemicals: solutions for metal contaminants in hydrocarbon processing
Speaker: Andrew Brotherhood, Agilent, UK

General Consumables Talks:

- Worry Less, Analyze More: advances in ICP-OES sample introduction systems
Speaker: Lindsey Whitecotton, Agilent, USA
- Maximize your ICP-OES instrument performance and uptime
Speaker: Lindsey Whitecotton and Eric Vanclay, Agilent, USA and Australia
- Application specific configurations for ICP-MS sample introduction
Speaker: Gareth Pearson and James Dellis, Agilent, Australia

Troubleshooting Talks, Hints and Tips:

- Troubleshooting with AAS (Part 1 – 3)
Speaker: Eric Vanclay, Agilent, Australia
- Troubleshooting with ICP-MS (Part 1 – 4)
Speaker: Eric Vanclay, Agilent, Australia
- Troubleshooting with ICP-OES (Part 1 – 4)
Speaker: Eric Vanclay, Agilent, Australia

Service and After Sales:

- Real life challenges and solutions seen with CSD Projects
Speakers: Therese Heffernan & Greg Shaw, Agilent, Ireland and UK
- How to efficiently and cost effectively execute Computer Systems Verification
Speakers: Therese Heffernan & Greg Shaw, Agilent, Ireland and UK
- Minimize regulatory risk by moving to a customized instrument qualification solution
Speaker: Garry Wright, Agilent UK

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